



NCR Number

NCR/FM/INFN/RM2/1

<i>Classification</i>	<i>Item name</i>	<i>Found on:</i>
major	fid-Tray Composite Panel Assembl	06/18/2004 4:13:41 PM

Part number LAT-DS-00180(rev3)

Serial number 006, 008, 015

Issued by Francesco Belli

Short NCR description Bias circuits delaminations

Approved by Alessandro Brez

Detected during T. Vac test

Cause other (see description)

NCR description Bias circuits delamination found after the thermo-vacuum test. See annex 1.

Action Refer MRB

disposition

<u>disposition ID:</u> 1		
INFN pisa suggest to perform investigation in order to verify the cause of the NCR. INFN/Pisa is a waiting for SLAC MRB		
<u>Finding</u>		
<u>responsible</u> Alessandro Brez	<u>due date (mm/dd/yyyy)</u> 06/21/2004	<u>closed</u> <input type="checkbox"/>

MRB disposition

Approval date

Signature

Customer approval date

NCR status

open

Annex

<u><i>annex N°</i></u>	<u><i>Identification</i></u>
1	Test results images.

<u><i>annex N°</i></u>	<u><i>Identification</i></u>
2	Test results

ANNEX 1 to NCR/FM/INFN/RM2/001

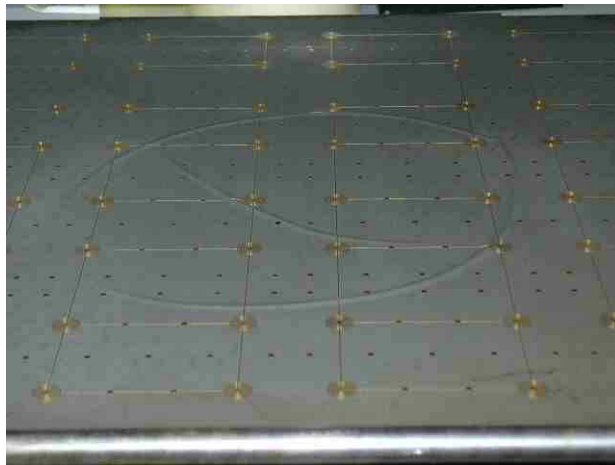
Thermo-vacuum test results

The following images shows the effect of the test on the trays Mid 006, Mid 008, Mid 015.

Tray Mid 006:



Tray Mid 008:



Tray Mid 015:

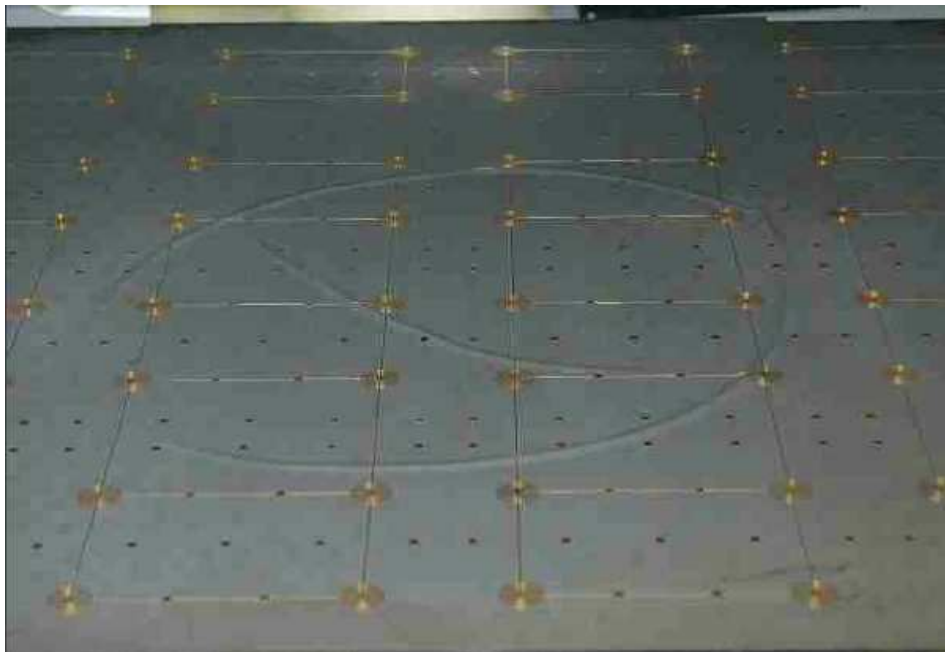


Annex 2 to NCR/FM/INFN/RM2/001

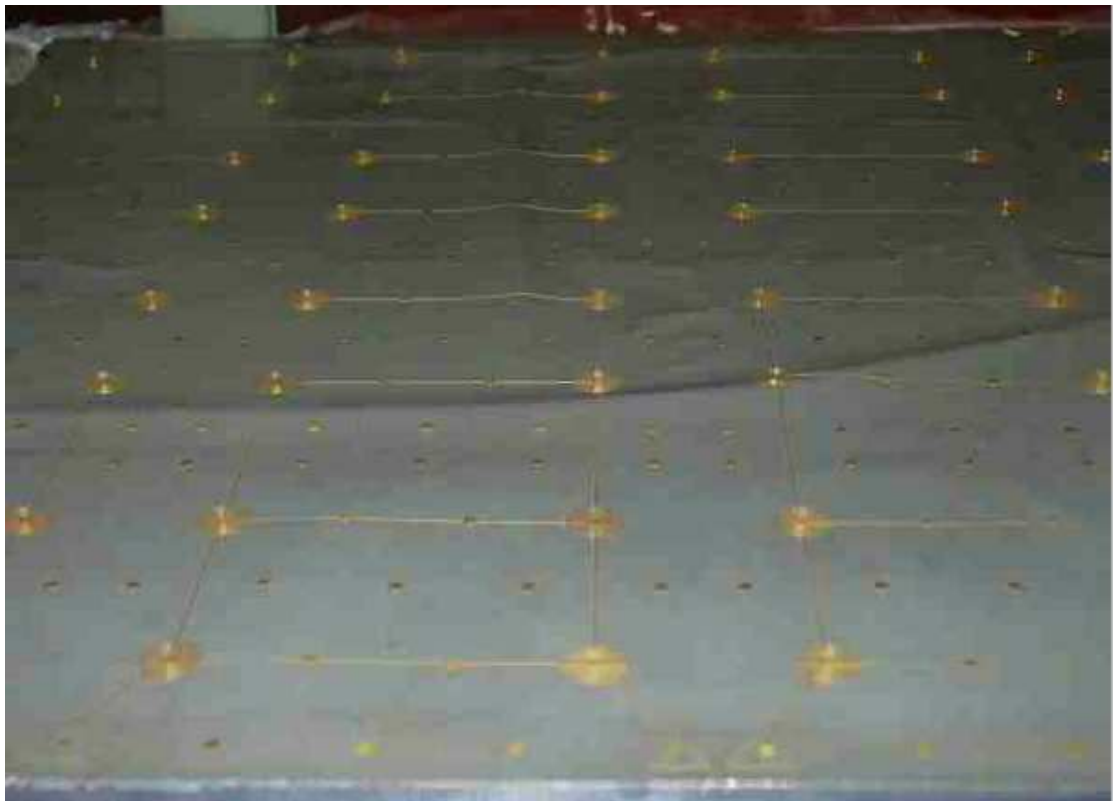
The Thermo Vacuum Test of the trays Mid006, Mid008, Mid015, failed. The bonding between the Bias Circuit Foils and the panels relaxed and the foils showed a large surface wrinkling (see picture 1, 2, 3, 4):



Mid006 Bottom Surface



Mid008 Top Surface



Mid008 Bottom Surface



Mid008 Bottom Surface

These large debonding areas seem induced by the CTE differences between Cu shield layer ($CTE = 17 \cdot 10^{-6} 1/^\circ C$) and the tray ($CTE \approx 0$). The Shear Stress overcame The shear strength of the adhesive with regular and uniform deformations.

The Glue used for this bonding is the **3M Scotch-Weld 2216**, the Bias Circuit is similar to the one used for the Top and the Bottom tray in the EM tower. The assembly procedure and tools are the same used for the EM Trays.

The EM Tower has been successfully tested in the following temperature range: **$-30^\circ C + 50^\circ C$** .

The Inspections of the EM trays don't show any failure.

The Thermo Vacuum Procedure has a temperature range that exceeds the design test range for the LAT Tracker Specifications (min $-30^\circ C$, max $+50^\circ C$).

The Peak temperature of this test is $85^\circ C$; the **3M Scotch-Weld 2216** epoxy glue data sheet shows a relevant decrease of the typical Shear Properties (see table below):

Test Temperature	Overlap Shear (psi)
$24^\circ C$	3200
$82^\circ C$	400

We suggest to decrease the Peak temperature of the Thermo Vacuum test of the trays from $85^\circ C$ to $55^\circ C$, $5^\circ C$ Higher than the requested max temperature as for LAT-TD-03651.

To validate the test we plan to perform the following tests:

- 1) Vacuum test of 4 trays at room temperature
- 2) If no debonding will be observed, perform a Vacuum test @ $55^\circ C$ for 4 hours

Due to the relevance of the peak temperature a revision of the Set-Up and Test Procedure will be done.